

**Search Notes**

Application/Control No.

10/780,170

Examiner

Fenn C. Mathew

Applicant(s)/Patent under  
Reexamination

VANG ET AL.

Art Unit

3764

**SEARCHED**

Class	Subclass	Date	Examiner
482	83.051		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR